

INFORMATION DISCLOSURE STATEMENT BY APPLICANT	Attorney Docket Number	1011-67627
	Application Number	Not yet assigned
	Filing Date	February 17, 2004
	First Named Inventor	Rajski
	Art Unit	--
	Examiner Name	--

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
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<i>JA</i>		3,614,400	Oct-71	Farnett
		3,700,869	Oct-72	Low et al.
		4,503,537	Mar-85	McAnney
		4,513,418	Apr-85	Bardell, Jr., et al.
		4,602,210	7/1986	Fasang et al.
		4,687,988	Aug-87	Eichelberger et al.
		4,754,215	Jun-98	Kawai
		4,785,410	Nov-88	Hamatsu et al.
		4,801,870	Jan-89	Eichelberger et al.
		4,860,236	Aug-89	McLeod et al.
		4,959,832	Sep-90	Bardell, Jr.
		4,974,184	Nov-98	Avra
		5,090,035	Feb-92	Murase
		5,138,619	Aug-92	Fasang et al.
		5,173,906	Dec-92	Dreibelbis et al.
<i>JA</i>		5,268,949	Dec-93	Watanabe

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		5,790,562	Aug-98	Murray et al.

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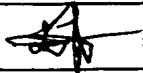

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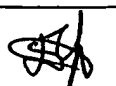

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Examiner's Initials*	Cite No. (optional)	Number	Date	Country
		WO 01/38889 A1	31 May 2001	PCT



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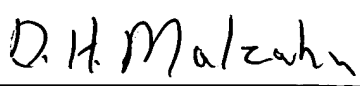
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

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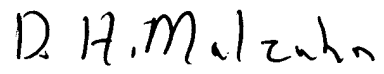
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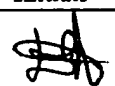
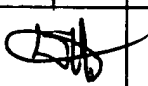
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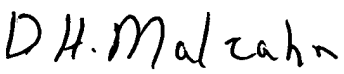
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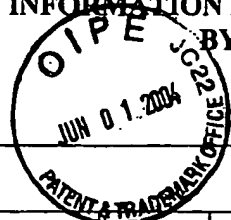
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<i>[Signature]</i>		20020124217	9.5.2002	Hiraide et al.

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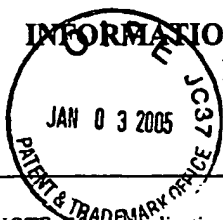
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**INFORMATION DISCLOSURE STATEMENT
BY APPLICANT**

JAN 03 2005



Attorney Docket Number	1011-67627-01
Application Number	10/781,031
Filing Date	February 17, 2004
First Named Inventor	Rajski
Art Unit	2124
Examiner Name	

U.S. PATENT DOCUMENTS

NOTE: If the application was filed after June 30, 2003, copies of United States patents and United States published patent applications do not have to be provided to the Patent Office. This requirement of 37 C.F.R. § 1.98(a)(2)(i) has been waived by the United States Patent and Trademark Office pursuant to the Official Gazette Notice on August 5, 2003 (1276 OG 55).

Examiner's Initials*	Cite No. (optional)	Number	Publication Date	Name of Applicant or Patentee
<i>[Signature]</i>		4,536,881	8.20.1985	Kasuya
		5,202,889	4.13.1993	Aharon et al.
		5,701,308	12.23.1997	Attaway et al.
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		6,122,761	9.19.2000	Park
<i>[Signature]</i>		6,829,740	12.7.2004	Rajski et al.

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Examiner's Initials*	Cite No. (optional)	Number	Filing Date	Name of Applicant
<i>[Signature]</i>		09/620,021	7.21.2000	Rajski et al.

FOREIGN PATENT DOCUMENTS

Examiner's Initials*	Cite No. (optional)	Country	Number	Publication Date	Name of Applicant or Patentee
<i>[Signature]</i>		Europe	EP 0372226	6.13.1990	Bardell
<i>[Signature]</i>		Europe	EP 0438322	7.24.1991	Murase
<i>[Signature]</i>		Europe	EP 0481097	4.22.1992	Diebold et al.

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



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				Art Unit	2124
				Examiner Name	
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		Japan	JP 4-236378	8.25.1992	Diebold et al.
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		Bassett et al., "Low-Cost Testing of High-Density Logic Components," <i>IEEE Design & Test of Computers</i> , pp. 15-28 (April 1990).			
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